

报告编号 (Report No.)	XDWH-IC-20230013
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检测报告

Test Report

产品名称: Silicon Carbide Schottky Diode
Product

型号规格: TD5G20065RA
Model

生产单位: TOPE Technologies Co., Ltd.
Manufacturer

委托单位: TOPE Technologies Co., Ltd.
Client

西安电子科技大学芜湖研究院
芯片及电子系统检测中心

Chip and Electronic System Testing Center,
XIDIAN-WUHU RESEARCH INSTITUTE

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"judgment" or "result" of "P" in the report indicates that the test is "qualified"; "F" indicates that the test is "non-conforming"; "NA" indicates that the test is not applicable; "ND" indicates that the detection is not detected; "—" indicates that the item does not need to be judged.

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Test results and test reports must not be used for improper or illegal publicity.

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检测报告

Test Report

样品名称 Product	Silicon Carbide Schottky Diode	型号规格 Model	TD5G20065RA/650V,20A
		商标 Trademark	/
生产单位 Manufacturer	TOPE Technologies Co., Ltd.	检测类别 Test category	Entrustment Inspection
委托单位 Client	TOPE Technologies Co., Ltd.	检测地点 Lab location	Chip and Electronic System Testing Center
生产方地址 Manufacture address	Building B3, Wuhu Technology Industrial Park, High-tech Industrial Development Zone, Wuhu City, Anhui Province		
委托方地址 Client address	Building B3, Wuhu Technology Industrial Park, High-tech Industrial Development Zone, Wuhu City, Anhui Province		
样品数量 Sample size	1406	收样日期 Sample date	2023 年 3 月 15 日
送样人 Sample Sender	The same as Client	检测日期 Test date	2023 年 3 月 15 日 至 2023 年 5 月 15 日
检测环境 Ambient condition	温度 TEMP.:18℃~28℃ 相对湿度 R.H.:20%~75% 气压 Atmospheric Pressure:86kPa~106kPa		
检测项目 Test item	Refer to Test item and result on page 4		
检测依据 Test Method	Refer to Test method list on page 4		
检测结论 Conclusion	The center conducted AEC-Q101 standard test on the Silicon Carbide Schottky Diode typed TD5G20065RA as required by the client, and the result was qualified and compliant with AEC-Q101.  (检测单位公章)		
说明 Remark	<ol style="list-style-type: none"> Sample distribution table is shown in Table 2. Annex 1 is also attached to this report, which contains electrical parameters and test result of the test items. 		

主检: 赵磊
Tested by: 赵磊

审核: 王旭东
Reviewer: 王旭东

批准: 梁金峰
Approval: 梁金峰

日期: 2023.5.15
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